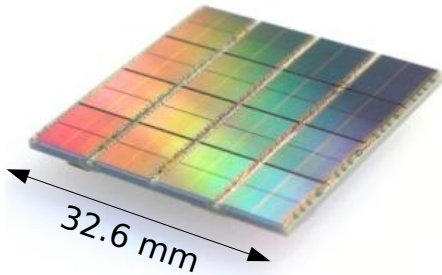


Radition hardness study of the Philips Digital Photon Counter with proton beam

M.Yu. Barnyakov, S.A. Kononov, I.A. Kuyanov, V.G. Prisekin (*Budker Institute of Nuclear Physics, Novosibirsk, Russia*)
 T. Frach (*Philips Digital Photon Counting, Aachen, Germany*)

DPC3200-22-44

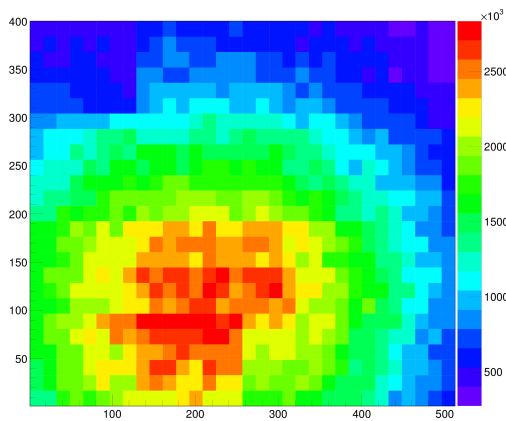


Array of 4x4 die.

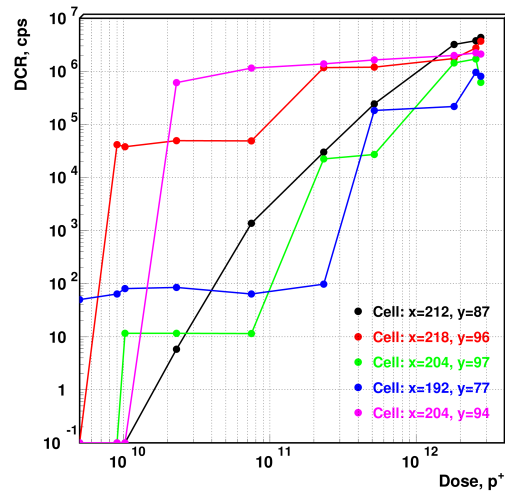
Die = 128x100 cells (Geiger-mode APDs) +
 + TDC (LSB=20ps) + 4 photon counters.

Active cell quenching.
 Full digital data output.
 Noisy cells can be disabled.

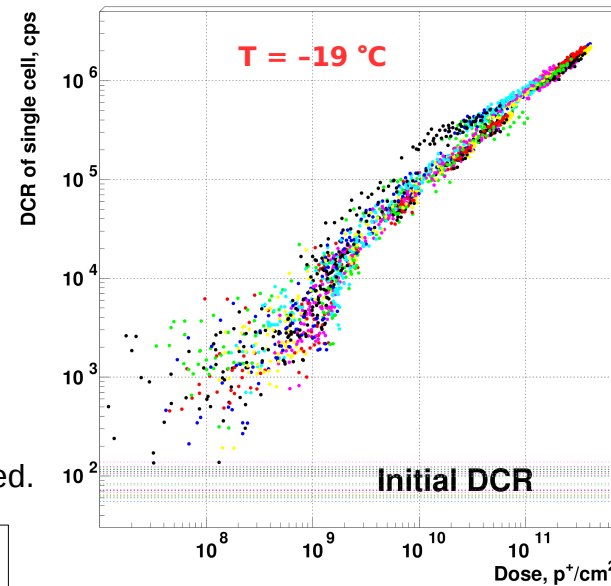
Irradiation by protons with $P=800\text{MeV}/c$ ($T=295\text{MeV}$).
 Beam size: $\sigma_x \approx \sigma_y \approx 1\text{ cm}$.



Dark counting rate (DCR) map
 after irradiation.



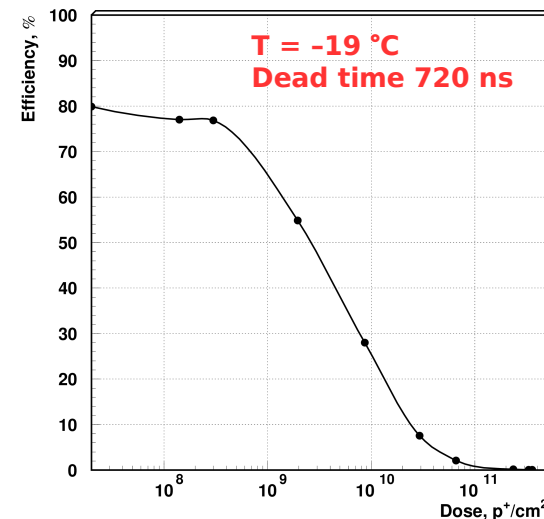
Step-like increase of cell DCR
 caused by single interactions of
 protons with Si lattice.



At maximum accumulated
 proton fluence of $4 \times 10^{11}\text{ cm}^{-2}$
 DCR increased by ~ 4 orders
 of magnitude.

DCR of irradiated detector
 is less sensitive to
 the temperature variation
 \Rightarrow DCR reduction by cooling
 down becomes less efficient.

Average dose between FPGA failures is $\sim 140\text{ rad}$.
 Functionality can be fully restored by initialization.



The DCR increase
 caused by irradiation
 results in loss of single
 photon detection
 efficiency due to the total
 dead time increase.

Optimal efficiency at each
 fluence is a tradeoff
 between fraction of active
 cells and total dead time.